



FQB6N40CF 400V N-Channel MOSFET

Features

- 6A, 400V, $R_{DS(on)} = 1.1 \Omega$ @ $V_{GS} = 10$ V
- Low gate charge (typical 16nC)
- Low C_{RSS} (typical 15pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- Fast recovery body diode (typical 70ns)

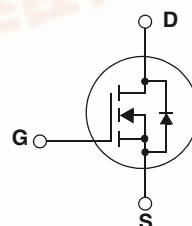
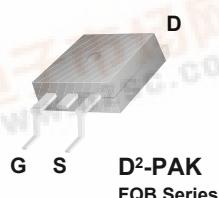
December 2005

FRFET™

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, electronic lamp ballasts based on half bridge topology.



Absolute Maximum Ratings

Symbol	Parameter	FQB6N40CF	Units
V_{DSS}	Drain-Source Voltage	400	V
I_D	Drain Current - Continuous ($T_C = 25^\circ\text{C}$)	6	A
	- Continuous ($T_C = 100^\circ\text{C}$)	3.8	A
I_{DM}	Drain Current - Pulsed	(Note 1)	A
V_{GSS}	Gate-Source Voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	mJ
I_{AR}	Avalanche Current	(Note 1)	A
E_{AR}	Repetitive Avalanche Energy	(Note 1)	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	V/ns
P_D	Power Dissipation ($T_C = 25^\circ\text{C}$)	113	W
	- Derate above 25°C	0.9	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
T_L	Maximum lead temperature for soldering purposes, 1/8 Δ from case for 5 seconds	300	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	FQB6N40CF	Units
R_{QJC}	Thermal Resistance, Junction-to-Case	1.1	$^\circ\text{C/W}$
R_{QJA}	Thermal Resistance, Junction-to-Ambient *	40	$^\circ\text{C/W}$
R_{QJA}	Thermal Resistance, Junction-to-Ambient	62.5	$^\circ\text{C/W}$

When mounted on the minimum pad size recommended (PCB Mount)



Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQB6N40CF	FQB6N40CFTM	D ² -PAK	330mm	24mm	800

Electrical Characteristics

$T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0 \text{ V}, I_D = 250 \mu\text{A}$	400	--	--	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C	--	0.54	--	$\text{V}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 400 \text{ V}, V_{\text{GS}} = 0 \text{ V}$	--	--	10	μA
		$V_{\text{DS}} = 320 \text{ V}, T_C = 125^\circ\text{C}$	--	--	100	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{\text{GS}} = 30 \text{ V}, V_{\text{DS}} = 0 \text{ V}$	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{\text{GS}} = -30 \text{ V}, V_{\text{DS}} = 0 \text{ V}$	--	--	-100	nA
On Characteristics						
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250 \mu\text{A}$	2.0	--	4.0	V
$R_{\text{DS(on)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}} = 10 \text{ V}, I_D = 3 \text{ A}$	--	0.9	1.1	Ω
g_{FS}	Forward Transconductance	$V_{\text{DS}} = 40 \text{ V}, I_D = 3 \text{ A}$ (Note 4)	--	4.7	--	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{\text{DS}} = 25 \text{ V}, V_{\text{GS}} = 0 \text{ V}, f = 1.0 \text{ MHz}$	--	480	625	pF
C_{oss}	Output Capacitance		--	80	105	pF
C_{rss}	Reverse Transfer Capacitance		--	15	20	pF
Switching Characteristics						
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}} = 200 \text{ V}, I_D = 6 \text{ A}, R_G = 25 \Omega$	--	13	35	ns
t_r	Turn-On Rise Time		--	65	140	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time		--	21	55	ns
t_f	Turn-Off Fall Time		--	38	85	ns
Q_g	Total Gate Charge	$V_{\text{DS}} = 320 \text{ V}, I_D = 6 \text{ A}, V_{\text{GS}} = 10 \text{ V}$	--	16	20	nC
Q_{gs}	Gate-Source Charge		--	2.3	--	nC
Q_{gd}	Gate-Drain Charge		--	8.2	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current	--	--	6	--	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	24	--	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{\text{GS}} = 0 \text{ V}, I_S = 6 \text{ A}$	--	--	1.4	V
t_{rr}	Reverse Recovery Time	$V_{\text{GS}} = 0 \text{ V}, I_S = 6 \text{ A}, dI_F / dt = 100 \text{ A}/\mu\text{s}$	--	70	--	ns
Q_{rr}	Reverse Recovery Charge	(Note 4)	--	0.12	--	μC

NOTES:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. $L = 13.7\text{mH}, I_{AS} = 6\text{A}, V_{DD} = 50\text{V}, R_G = 25 \Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{SD} \leq 6\text{A}, di/dt \leq 200\text{A}/\mu\text{s}, V_{DD} \leq \text{BV}_{\text{DSS}}$, Starting $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
5. Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

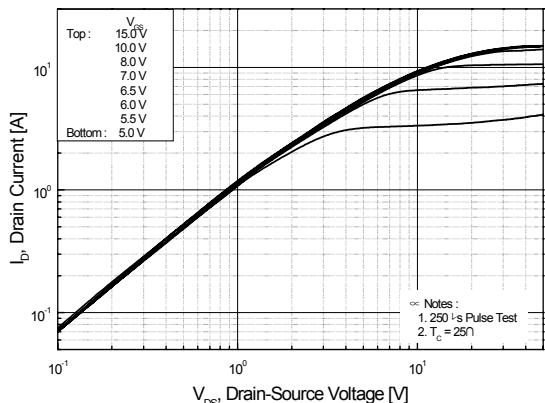


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

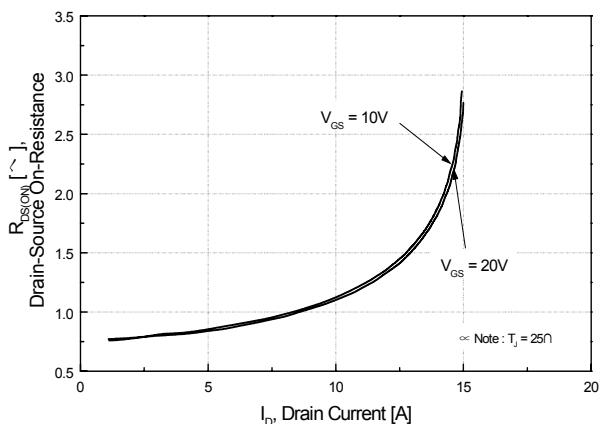


Figure 5. Capacitance Characteristics

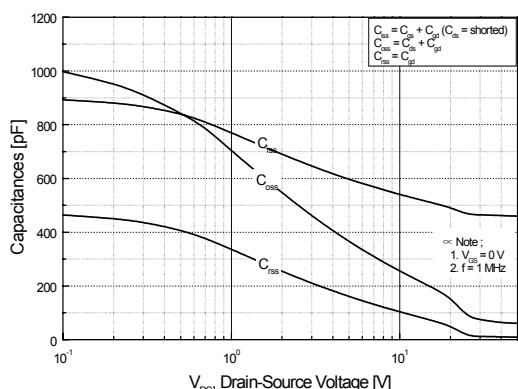


Figure 2. Transfer Characteristics

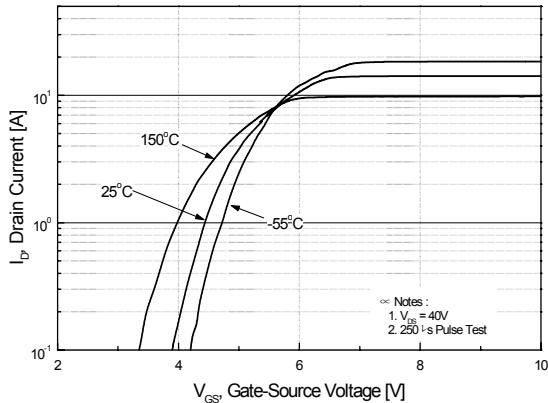


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

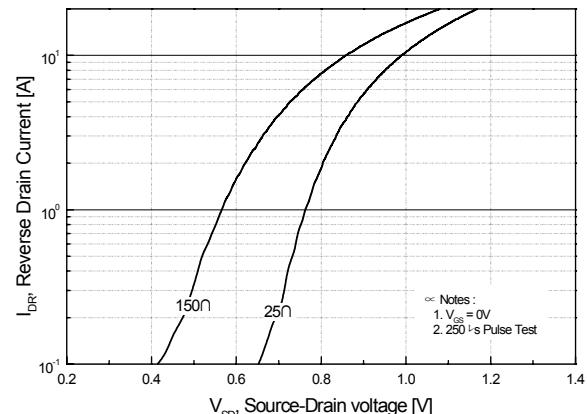
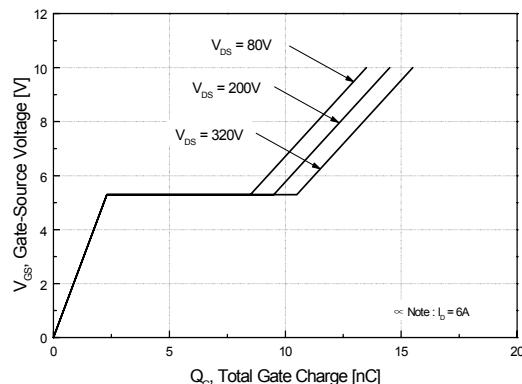


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

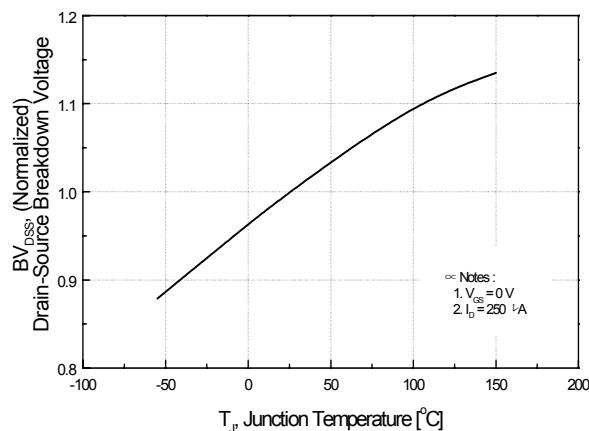


Figure 9. Maximum Safe Operating Area

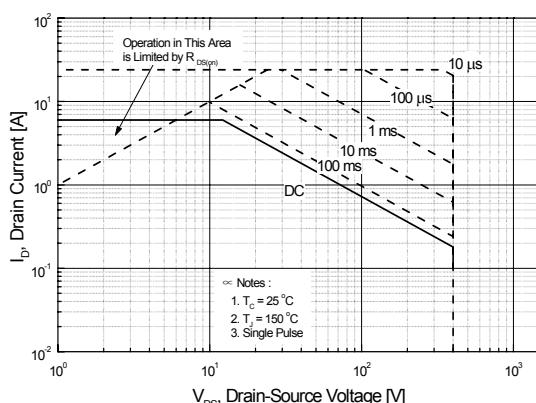


Figure 11. Transient Thermal Response Curve

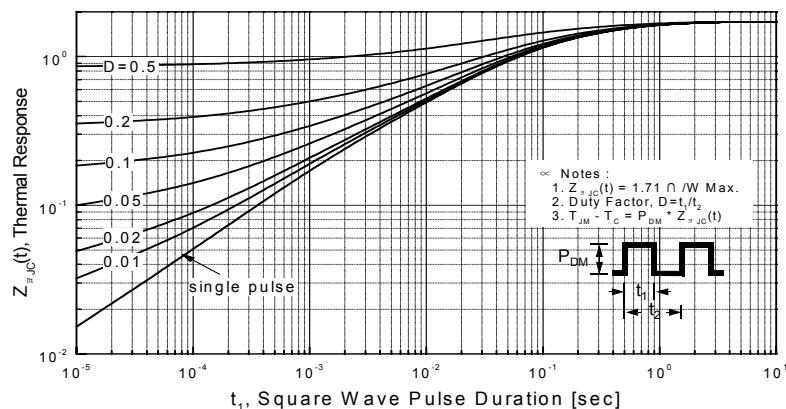


Figure 8. On-Resistance Variation vs. Temperature

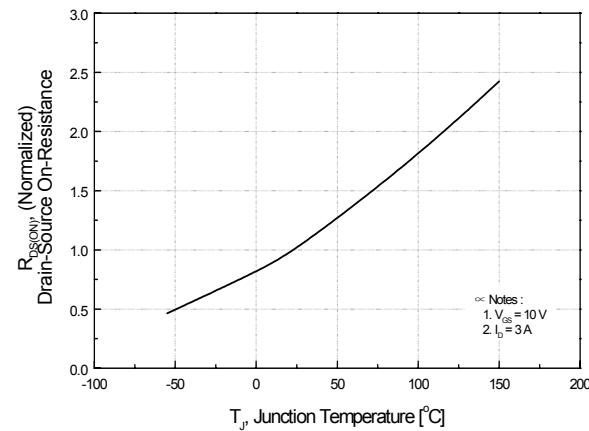
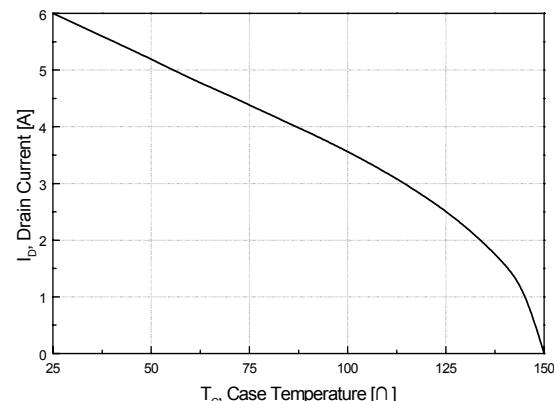
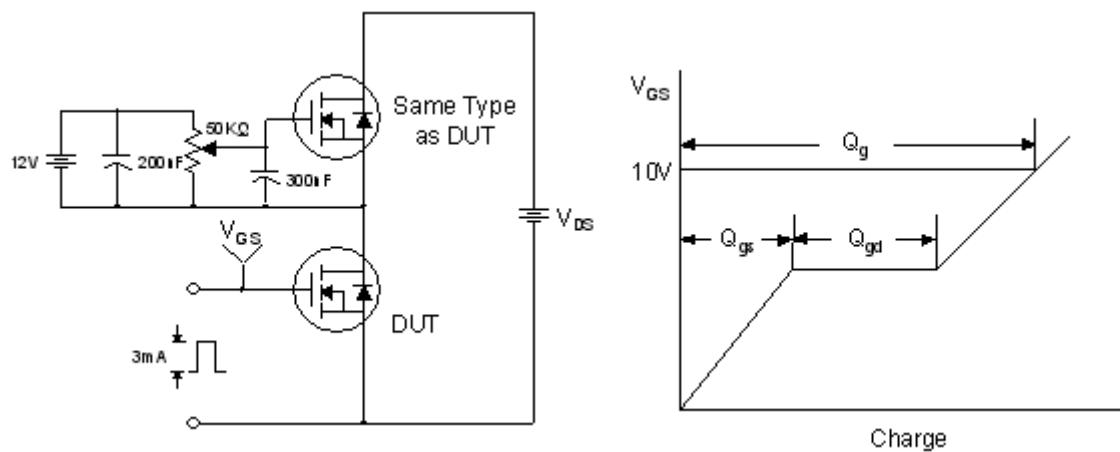


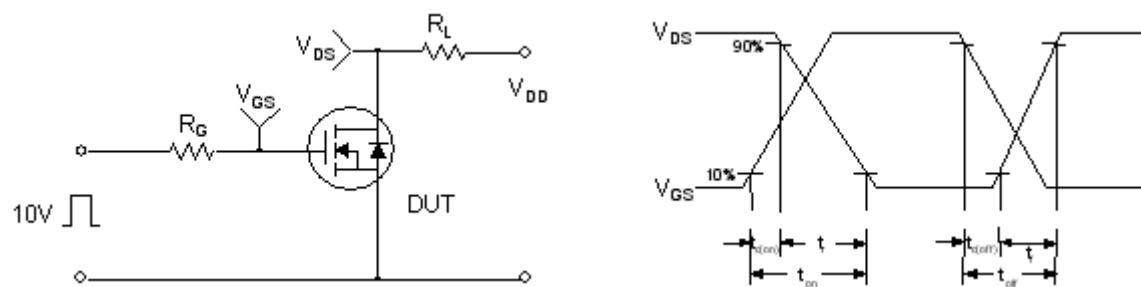
Figure 10. Maximum Drain Current vs. Case Temperature



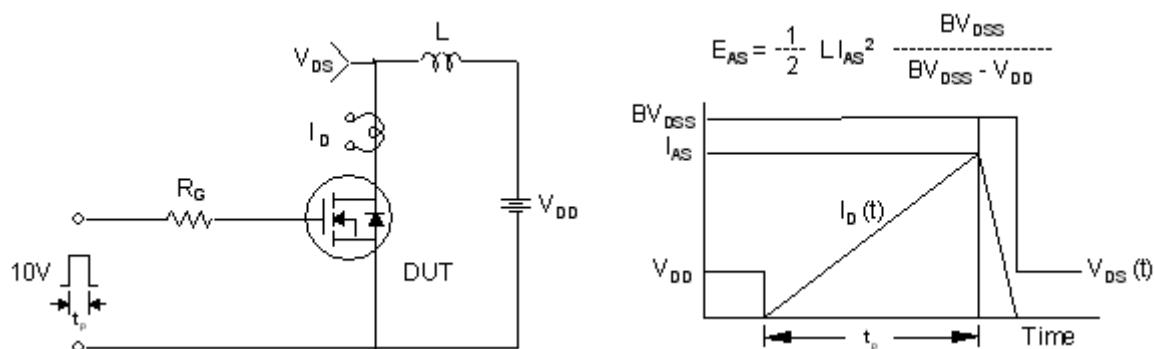
Gate Charge Test Circuit & Waveform



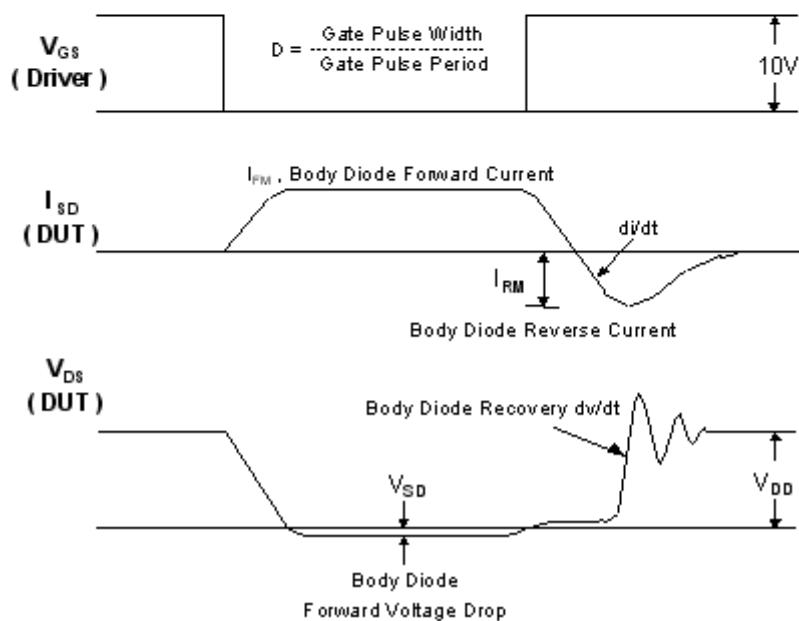
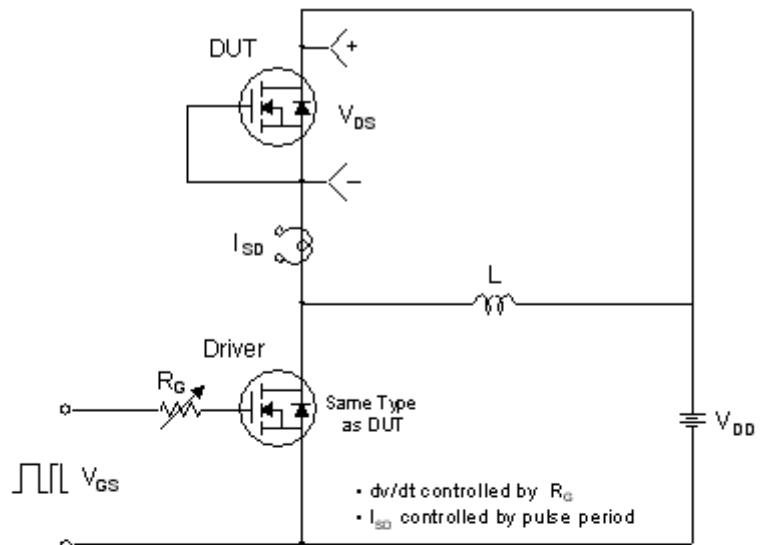
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

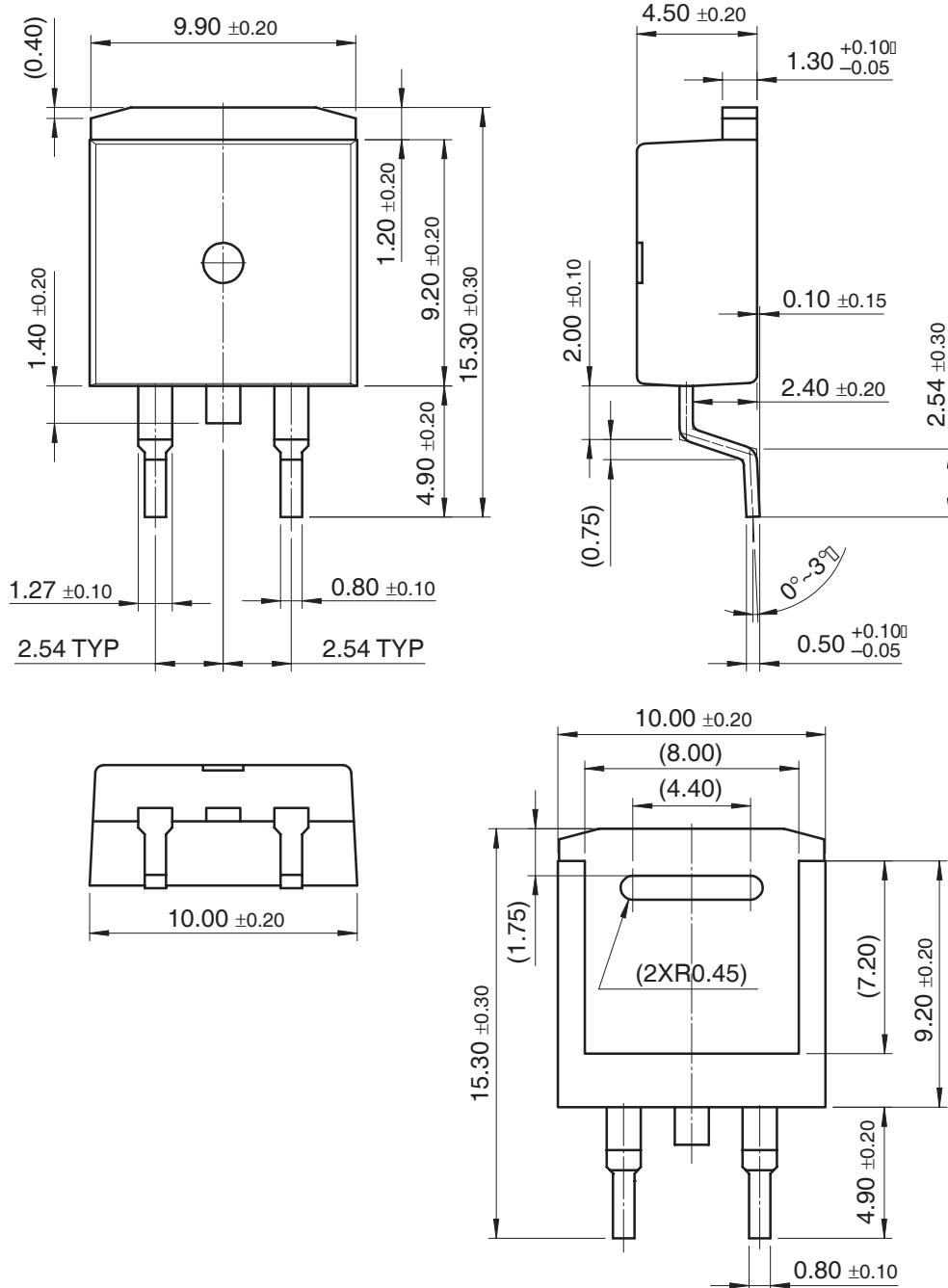


Peak Diode Recovery dv/dt Test Circuit & Waveforms



Mechanical Dimensions

D²-PAK



Dimensions in Millimeters

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